

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 10/784,238 | Applicant(s)/Patent Under Reexamination BONICEL ET AL. | |
| | Examiner Hae M Hyeon | Art Unit 2839 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------------|----------------|
| | A | US-3,485,940 | 12-1969 | FREY ALBERT M; et. al. | 174/139 |
| | B | US-4,212,696 | 07-1980 | Lusk et al. | 156/294 |
| | C | US-4,610,033 | 09-1986 | Fox, Jr., Frederick L. | 398/141 |
| | D | US-5,204,926 | 04-1993 | Bottoms et al. | 385/105 |
| | E | US-5,637,827 | 06-1997 | Goch, Waymon P. | 174/30 |
| | F | US-5,761,361 | 06-1998 | Pfandl et al. | 385/100 |
| | G | US-6,035,087 | 03-2000 | Bonicel et al. | 385/109 |
| | H | US-6,507,692 | 01-2003 | Hoefner et al. | 385/136 |
| | I | US-6,654,525 | 11-2003 | Nechitailo et al. | 385/103 |
| | J | US-5,224,190 | 06-1993 | Chu et al. | 385/107 |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.